

Form PTO-1449 (REV. 1/06)	US Dept. of Commerce PATENT & TRADEMARK OFFICE	ATTY DOCKET NO. 128977	APPLICATION NO. 10/588,297
INFORMATION DISCLOSURE STATEMENT  (Use several sheets if necessary)		APPLICANT(S) Naoyuki KOBAYASHI et al.	
		FILING DATE August 2, 2006	GROUP 2851

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EXAMINER <i>/Mesfin Asfaw/</i>	DATE CONSIDERED <i>10/18/2010</i>
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